## IN THE CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in the application: Listing of Claims:

1. (currently amended)	An x-ray examination apparatus comprising an x-ray source
and an x-ray detector,	
the x-ray detector	or including having
a photoconducto	or to derive electric charges from incident x-radiation and
read-out elemen	ts whichthat derive electrical pixel-signals from the electric charge
fromof the photoconductor and	
an output circuit	to output the electrical pixel-signal from the read-out elements,
wherein	
a central group o	of the read-out elements is located in a central region of the x-ray
detector and	
a peripheral group of the	e read-out elements is located in a peripheral region which that
surrounds the central region,	
the x-ray examination a	pparatus being provided with further having
a selection system to sel	lect the central group of read-out elements so as to supply pixel-
signals from the central group of	of read-elements to the output circuit.

2. (currently amended)

AnThe x-ray examination apparatus as claimed in Claimed

claim 1, wherein the selection system includes an x-ray shielding member which that shields the
peripheral region of the photoconductor from incident x-radiation.

DE020240 P.ATENT
Serial No. 10/35,058
Response to Office Action of August 11, 2006

3. (currently amended)

An The x-ray examination apparatus as-elaimed in Claim of claim 1, and further comprising a collimator between the x-ray detector, wherein the collimator comprises has an x-ray absorbing member which tall is spatially registered with the peripheral region of the photoconductor.

4. (currently amended). An-The x-ray examination apparatus as elaimed in Claim of claim 1, wherein and wherein the selection system includes has an encompassing electrode which surrounds at least substantially surrounding the central region and which is electrically connected to the read-out elements of the peripheral group.

5. (currently amended)

An The x-ray examination apparatus as elaimed in Claimof

claim 1, wherein collecting electrodes of read-out elements of the peripheral group are smaller sized than collecting electrodes of the read-out elements the central group.

6. (currently amended)

An-The\_x-ray examination apparatus as elaimed in Claim of

claim 1, wherein the selection system electrically isolates the peripheral group of read-out elements

from the output circuit.

7. (currently amended)

An The x-ray examination apparatus as elaimed in Claim of claim 1, wherein the photoconductor is a continuous semiconductor layer or the photoconductor includes a plurality of crystalline semiconductor elements.

8. (currently amended)

AnThe x-ray examination apparatus as elaimed in Claimof

claim 7, wherein the semiconductor layer or the semiconductor elements contain a photoconducting
material from the group of Cadmium Zinc Telluride, Mercury Iodide or Lead Oxide.